

# Effect of oxidizing and reducing atmospheres on the electrical properties of dense SnO<sub>2</sub>-based varistors

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Received 28 October 1999; received in revised form 26 May 2000; accepted 11 June 2000

## Abstract

The SnO<sub>2</sub> based varistor systems recently presented in the literature appear to have a promising potential in commercial applications. Experimental evidence shows that there is a dependence of nonlinear constant values with thermal treatment under different atmospheres. Thermal treatments in oxygen and nitrogen rich atmospheres at 900°C prove this dependence, indicating that the nonlinear constant values are significantly lower when the material is submitted to a nitrogen atmosphere. Moreover, electrical properties can be restored when the varistor is subjected to thermal treatment at the same temperature in an oxygen atmosphere, indicating that the mechanism seems to be reversible. This paper discusses this behavior focusing in the grain boundary region. Ta<sub>2</sub>O<sub>5</sub> mol% concentrations are also analyzed and the results indicate an optimum Ta<sub>2</sub>O<sub>5</sub> concentration of 0.05 mol% for the electrical properties ( $\alpha=44$  and  $E_B=6150$  V cm<sup>-1</sup>). © 2001 Elsevier Science Ltd. All rights reserved.

**Keywords:** Electrical properties; Grain boundaries; SnO<sub>2</sub>; Ta<sub>2</sub>O<sub>5</sub>; Varistors

## 1. Introduction

Varistors are materials whose current-voltage characteristics are nonlinear. They are used both as protecting devices against voltage transients in electronic and industrial equipment and as surge arrestors.<sup>1</sup> Commercial varistors used in protection systems are based on SiC (silicon carbide) or on ZnO (zinc oxide). SiC based varistors have low nonlinearity coefficients ( $\alpha=5$ ) where  $\alpha$  is the nonlinearity constant defined by the relation of ( $I=KV^\alpha$ ), where  $I$  is current,  $V$  is voltage and  $K$  is a proportionality constant.<sup>2</sup>

The ZnO based varistors have very high nonlinearity coefficients ( $\alpha=50$ ) and their major phase consists of ZnO and of small amounts of Bi<sub>2</sub>O<sub>3</sub>, Sb<sub>2</sub>O<sub>3</sub>, CoO, MnO<sub>2</sub> and Cr<sub>2</sub>O<sub>3</sub>.<sup>3,4</sup> The reaction between the ZnO and the additives at high temperatures leads to the formation of several phases in the grain boundary of ZnO.<sup>5,6</sup> Thus, despite its chemical composition and its phases, the type of processing employed, as well as the sintering temperature, heating and cooling rates are fundamental

to control and understand electrical properties of this ceramic.<sup>7</sup> In view of this fact, the literature contains extensive reports describing the influence of processing variables on the properties and mechanisms that govern these systems' properties.<sup>8–14</sup>

Other varistor systems based on SrTiO<sub>3</sub>,<sup>15</sup> TiO<sub>2</sub><sup>16–19</sup> and, more recently, WO<sub>3</sub> varistors<sup>20</sup> have been described in the literature, but the nonlinearity of these systems is very low ( $2<\alpha<12$ ) compared with that of the multicomponent ZnO varistors. Pianaro et al.<sup>21</sup> were the first to present an SnO<sub>2</sub> based system as the main candidate to substitute multicomponent ZnO varistors. In this varistor system, the addition of CoO to the SnO<sub>2</sub> leads to high densification,<sup>21,22</sup> which makes it possible to define the varistors' behavior. A high nonlinearity coefficient of ( $\alpha=41$ ) was obtained in the SnO<sub>2</sub>·CoO·Nb<sub>2</sub>O<sub>5</sub> (1.0 mol% of CoO and 0.05 mol% of Nb<sub>2</sub>O<sub>5</sub>) system when 0.05 mol% of Cr<sub>2</sub>O<sub>3</sub> was added. The major advantage of this system lies in its simple single-phase microstructure and its high electrical stability.<sup>23</sup> From a technological standpoint, these two characteristics are very important because they increase the service life of the material and facilitate the control of its processing. Scientifically, they are important because

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they allow a direct study of the voltage barrier at the grain boundary and, therefore, a better understanding of varistor behavior and of the mechanisms that lead to this behavior.

Because we do not observe the segregation of the secondary phase in the  $\text{SnO}_2$  varistor systems, we propose that the potential barrier is formed by the presence of trap states. These trap states could be related to oxygen species ( $\text{O}_2$ ,  $\text{O}'_2$ ,  $\text{O}'$  and  $\text{O}''$ ) at the grain boundary interface due to defects such as  $\text{Cr}'_{\text{Sn}}$  and  $\text{Co}'_{\text{Sn}}$  that transfer electrons to oxygen.<sup>24</sup> In this work, we present results that demonstrate the importance of atmosphere for the nonlinear behavior of  $\text{SnO}_2$  based varistor systems. These results are important to detail the model of voltage barrier formation and  $\text{SnO}_2$  varistor behavior. The purpose of this study is also to determine the optimum  $\text{Ta}_2\text{O}_5$  concentration for the electrical properties of  $\text{SnO}_2$  varistor systems.

## 2. Experimental procedure

The powder was prepared using the ball milling process in an alcohol media. The oxides used were  $\text{SnO}_2$  (Merck),  $\text{CoO}$  (Riedel),  $\text{Ta}_2\text{O}_5$  (Aldrich) and  $\text{Cr}_2\text{O}_3$  (Vetec). The composition of the molar systems was  $(98.95-X)\% \text{ SnO}_2 + 1.0\% \text{ CoO} + X\% \text{ Ta}_2\text{O}_5 + 0.05\% \text{ Cr}_2\text{O}_3$  (SCTaCr), with X equal to 0.010, 0.035, 0.050 and 0.065%. Our chemical analysis of  $\text{SnO}_2$  indicated that the main impurities were Pb ( $<0.01\%$ ), Fe ( $<0.01\%$ ), Ge ( $<0.005\%$ ) and Cu ( $<0.005\%$ ), all in mol%.

The powder was pressed into pellets ( $11.0 \times 1.0$  mm) by uniaxial pressing (20 MPa), followed by isostatic pressing at 210 MPa. The pellets were sintered at  $1300^\circ\text{C}$  for 1 h and slowly cooled to room temperature. Mean grain size was determined by analyzing the SEM micrographies (ZEISS DSM 940A) using the PGT software (ASTM-E112 norm). To take the electrical measurements, silver contacts were deposited on the samples' surfaces, after which the pellets were heat treated at  $400^\circ\text{C}$  for 1 h.

The tetragonal structure of  $\text{SnO}_2$  (rutile structure) was confirmed as the single phase by X-ray diffraction (SIEMENS Model D-5000) on the mixed powder.

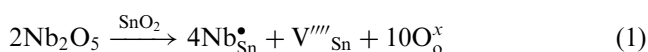
Current-tension measurements were taken using High Voltage Measure Unit (KEITHLEY Model 237). The nonlinear coefficient  $\alpha$  was obtained by linear regression of points on a logarithmic scale of around  $1 \text{ mA}\cdot\text{cm}^{-2}$  and the breakdown electric field ( $E_B$ ) was obtained at this current density.

The samples were subjected to treatments in  $\text{O}_2$  (under a flux of 10 l/min) and in  $\text{N}_2$  (under flux of 10 l/min) atmospheres at  $900^\circ\text{C}$  for 1 h. The electric behavior was checked throughout the above mentioned procedures and after each treatment.

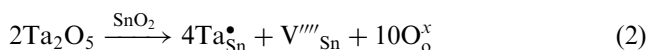
## 3. Results

### 3.1. Effect of $\text{Ta}_2\text{O}_5$ concentration on the properties of $\text{SnO}_2$ varistor

Recently, Antunes et al.<sup>25</sup> showed that the  $\text{Nb}_2\text{O}_5$  addition could be substituted in the same concentrations by  $\text{Ta}_2\text{O}_5$  in the  $\text{SnO}_2$  based varistor system without substantial alterations in its electric behavior. This indicates that the importance of this additive lies in its oxidation state (+5). As suggested by Pianaro et al.,<sup>21</sup>  $\text{Nb}_2\text{O}_5$  contributes to an increase of the electronic conductivity at the  $\text{SnO}_2$  lattice, due to the substitution of  $\text{Sn}^{+4}$  by  $\text{Nb}^{+5}$ , which creates an acceptor level according to the following reaction:



Similarly,  $\text{Ta}_2\text{O}_5$  contributes to an increase in the electronic conductivity in  $\text{SnO}_2$ , according to the reaction:



To verify the influence of  $\text{Ta}_2\text{O}_5$  on the varistor behavior of the  $\text{SnO}_2$  based system, compositions containing  $\text{Ta}_2\text{O}_5$  concentrations ranging from 0.010 to 0.065 mol% were considered. The samples with varying  $\text{Ta}_2\text{O}_5$  compositions were heat treated at  $900^\circ\text{C}$  in different atmospheres. The nonlinear coefficient ( $\alpha$ ) and breakdown electric field ( $E_B$ ) values are shown on Tables 1 and 2, respectively. There is an optimum concentration around 0.050 mol% of  $\text{Ta}_2\text{O}_5$  with a maximum value for nonlinear behavior and for the breakdown electric field ( $\alpha = 44$  and  $E_B = 6150 \text{ V/cm}$ ). Fig. 1 shows the  $J \times E$  plots for the  $\text{SnO}_2$  based systems with different  $\text{Ta}_2\text{O}_5$  concentrations. Fig. 2 shows the  $\alpha$  and  $E_B$  values based on  $\text{Ta}_2\text{O}_5$  mol% concentration for SCTaCr systems.

As shown in these two tables, the atmosphere strongly affects the nonlinear coefficient ( $\alpha$ ) and breakdown electric field ( $E_B$ ) values. Oxidizing atmospheres lead to high values for both,  $\alpha$  and  $E_B$ . One important point is that, after heat treatment in a reducing atmosphere ( $\text{N}_2$ ),  $\alpha$  and  $E_B$  values decrease substantially. However, both  $\alpha$  and  $E_B$  can be restored after subsequent heat treatment in an oxidizing atmosphere.

Table 3 shows the variation of  $\text{Ta}_2\text{O}_5$  concentration on average grain size. There is no significant difference in the samples average grain size, and variations in the electrical properties with atmosphere are due only to the oxidizing effect that facilitates interpretation of these results.

Fig. 3 contains the SEM micrographs of the systems considered in this study. Although no secondary phases

Table 1  
 $\alpha$  Values for SCTaCr systems after thermal treatments at 900°C in different atmospheres

Atmosphere treatments	0.010 mol%	0.035 mol%	0.050 mol%	0.065 mol%
Without treatment	3	32	44	23
O <sub>2</sub> 10 l/min flux	—	39	65	29
N <sub>2</sub> 10 l/min flux	—	15	21	17
O <sub>2</sub> 10 l/min flux (again)	—	36	54	24

Table 2  
 $E_B$  values in V/cm for SCTaCr systems after thermal treatments at 900°C in different atmospheres

Atmosphere treatments	0.010 mol%	0.035 mol%	0.050 mol%	0.065 mol%
Without treatment	2530	5820	6150	4800
O <sub>2</sub> 10 l/min flux	—	6180	6200	5000
N <sub>2</sub> 10 l/min flux	—	3220	5530	4200
O <sub>2</sub> 10 l/min flux (again)	—	6000	6300	4900

were observed in the SEM micrographs, these phases might be precipitated at the grain boundaries, such as CoSnO<sub>3</sub> and CoCr<sub>2</sub>O<sub>4</sub>.<sup>22</sup> The relative densities of all samples exceeded 98% of the theoretical density and, according to the XRD analysis and other works in the literature,<sup>21,25,26</sup> no other phases besides SnO<sub>2</sub> rutile were observed.

### 3.2. The effect of atmosphere on the current-voltage characteristics

To verify the effect of oxidizing atmosphere on the current-voltage characteristics of SnO<sub>2</sub> based varistors, samples containing 0.050 mol% of Ta<sub>2</sub>O<sub>5</sub> sintered in normal air ( $\alpha = 44$ ) were further heat treated at 900°C in an oxygen rich atmosphere. The  $\alpha$  value increased to 65. The same samples were then subjected to further heat treatment in nitrogen rich atmosphere and the  $\alpha$  decreased to as low as 21. This was followed by another heat treatment at 900°C in oxygen, which partially restored the  $\alpha$  value to 54. This cycling effect with the atmosphere is schematized in Fig. 4. This cycling effect is similar to that reported in ZnO based varistor system by Sonder et al.<sup>27</sup> Sonder et al. showed that restoration of the nonlinear current-voltage characteristics for totally reduced varistors requires much higher temperature (~600°C) than is required to degrade a totally oxidized one. It explains why the totally current-voltage characteristic restoration did not occur in our experiment.

There is ample evidence in the literature<sup>35–40</sup> to conclude that stability can be achieved in an otherwise unstable ZnO varistor when it is heated for several hours in an oxidizing atmosphere, preferably from 600 to 800°C. Based on the literature and on the results of this study, it is

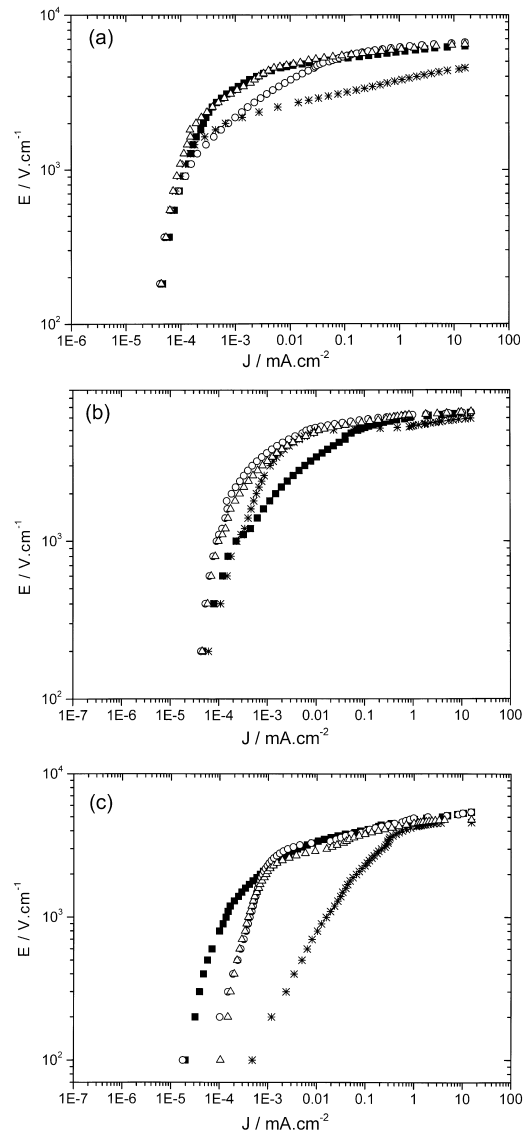


Fig. 1.  $J$ - $E$  characteristic curves for the systems (a) 0.035 mol% SCTaCr system; (b) 0.050 mol% SCTaCr system; (c) 0.065 mol% SCTaCr system. (■) Without treatment; (○) O<sub>2</sub> 10 l/min flux; (\*) N<sub>2</sub> 10 l/min flux; (△) new O<sub>2</sub> 10 l/min flux.

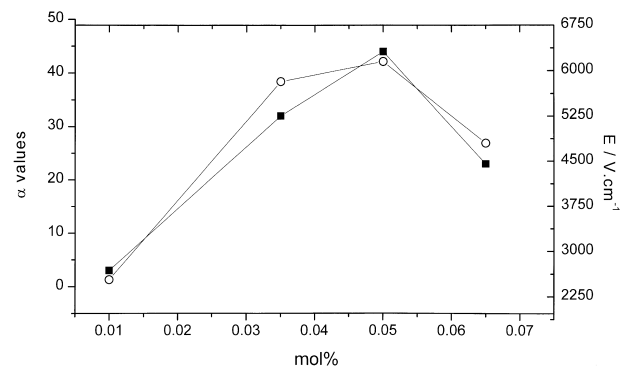


Fig. 2.  $\alpha$  (■) and  $E_B$  (○) values based on Ta<sub>2</sub>O<sub>5</sub> mol% concentration for SCTaCr systems without atmosphere treatment.

proposed that oxygen from the atmosphere is adsorbed at the grain boundary and diffuses throughout these disordered layers, represented by quasi-chemical reactions. The occurrence of oxygen grain boundary diffusion in polycrystalline oxides such as ZnO<sup>30,40</sup> has already been established in the literature describing sintering studies and this assumption is, therefore, not unrealistic.

Table 3  
Mean grain size and standard deviation of SCTaCr varistor systems

SCTaCr system (mol%)	Mean grain size (μm)	Standard deviation (μm)
0.010	4.5	2.1
0.035	4.6	2.1
0.050	4.8	2.2
0.065	4.8	2.2

Stucki et al. evidences that the height of potential barriers in ZnO varistors depends sensitively on the excess amount of oxygen (~1 monolayer) present at interfaces between grains.<sup>28</sup> This oxygen enrichment is influenced by thermal processing and by the electrical degradation.<sup>28</sup>

It was shown through complex plane analysis technique and Mott–Schottky approach that the barrier of ZnO and SnO<sub>2</sub> based varistor systems are of the same physical nature (Schottky-type barrier).<sup>29</sup> The results presented herein are in agreement and reinforce this observation.

The importance of the oxygen species for the formation of a voltage barrier in SnO<sub>2</sub> based varistor systems was discussed by Bueno et al.<sup>24</sup> The fact that the samples' varistor behavior is reversible when heat-treated in N<sub>2</sub> and O<sub>2</sub> indicates that there are very well defined adsorption sites. The results are also in agreement with

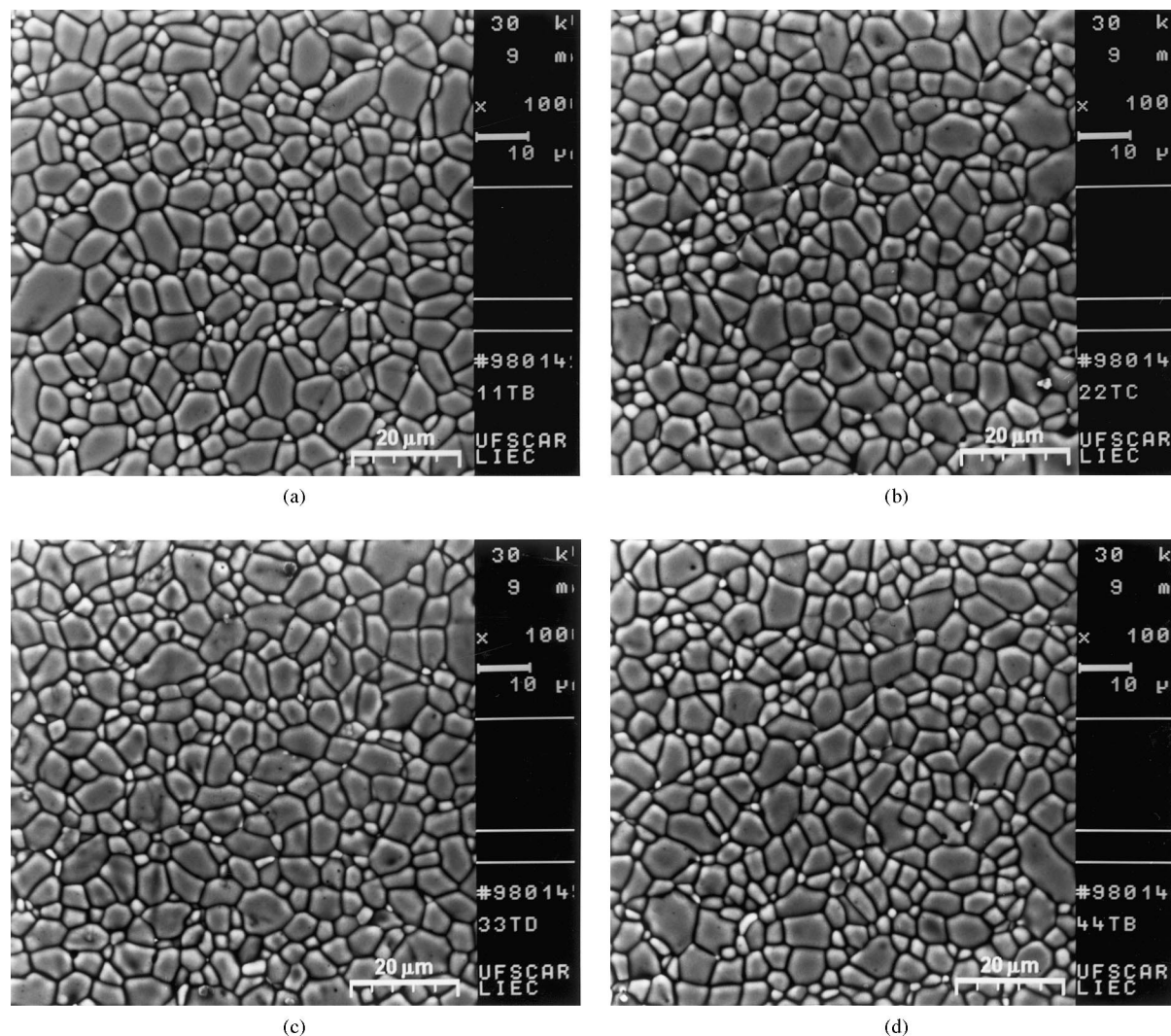


Fig. 3. SEM systems micrographs: (a) 0.010 mol% SCTaCr system; (b) 0.035 mol% SCTaCr system; (c) 0.050 mol% SCTaCr system; (d) 0.065 mol% SCTaCr system.

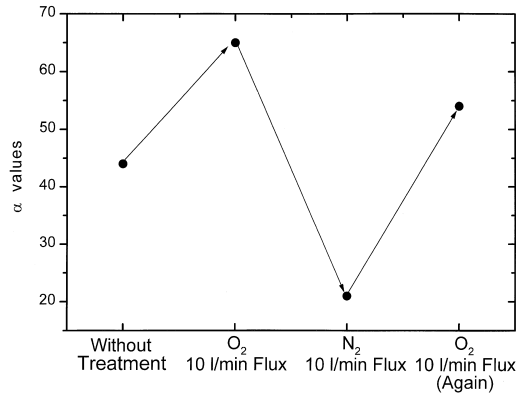
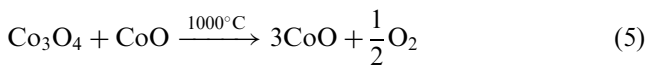
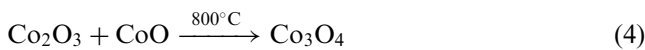
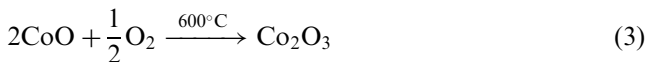


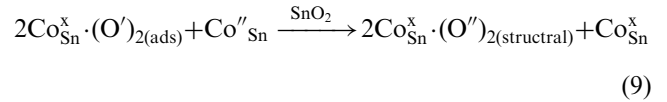
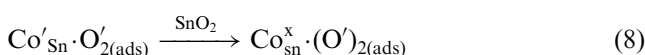
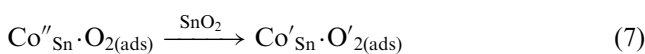
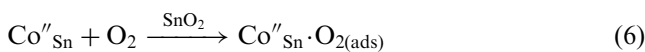
Fig. 4. Reversibility of  $\alpha$  values based on atmosphere treatments of 0.05 mol% SCTaCr system.

Gupta's model<sup>27</sup> modified by Leite et al.<sup>31,32</sup> to describe the voltage barrier in the ZnO based varistor system.

The mechanism of O<sub>2</sub> adsorption species in the SnO<sub>2</sub> based varistor has already been described and is linked with the Cr'<sub>Sn</sub> defect and the Co'<sub>Sn</sub>.<sup>24</sup> This mechanism is very important in understanding barrier formations in SnO<sub>2</sub> varistor systems. SnO<sub>2</sub> based varistor systems containing no Cr<sub>2</sub>O<sub>3</sub>, present low  $\alpha$  value ( $\alpha = 8$ ). However, optimizing the cooling rate during processing can increase this value. Lowering the cooling rate can cause the  $\alpha$  values to increase up to 24, as shown by Leite et al.<sup>33</sup> The increase in the  $\alpha$  values for slow cooling rates can be ascribed to the oxidizing effect of CoO during heating up to 600°C followed by the reducing effect at temperatures above 1000°C.<sup>34</sup> Eq. (3)–(5) represent CoO oxidation and reduction.



Therefore, the cobalt oxide, when in the +3 reduction state, can affect the adsorption of oxygen species in SnO<sub>2</sub> grain boundaries in a similar way as chromium oxide. Otherwise, when in the +2 state, the cobalt oxide can affect the adsorption of oxygen species in SnO<sub>2</sub> grain boundaries as represented by Eqs. (6)–(9).



Based on a theoretical study, Santos et al.<sup>41</sup> proposed a model in which Zn<sub>i</sub><sup>•</sup> species near the grain boundary decrease the negative surface state due to redistribution of the charge and favor oxygen adsorption. The adsorption of O', O<sub>2</sub>', and O<sub>2</sub> at the ZnO surface stabilizes the ZnO system, increasing the varistor properties. In their work, Santos et al.<sup>41</sup> proposed that desorption of these species leads to ZnO varistor degradation. Leite et al.<sup>31,32</sup> explain that the low degradation rate of ZnO based varistor in an oxygen rich atmosphere is due to the adsorption of O'' and O' species at the grain boundaries.

Thus, the adsorption phenomenon of the oxygen species in a disordered layer at the grain boundary seems to be largely responsible for the properties of varistor systems, since it is the dominant and extremely important mechanism for the performance of these ceramic devices. Fig. 5 depicts how O<sub>2</sub> species could interact with the grain boundary surface and modify the potential barrier in varistors.

Although the mechanisms that lead to the formation of electrical barriers in ZnO and SnO<sub>2</sub> based varistors appear to be similar, there are some basic differences between the two systems. SnO<sub>2</sub> varistors, differently from ZnO based varistors, need small dopant concentrations for good  $\alpha$  values. Ta<sub>2</sub>O<sub>5</sub> (+5 valence metals) amounts above 0.050 mol% do not promote an increase in  $\alpha$  values when treated in O<sub>2</sub> rich atmosphere. This may be explained by associating the Ta<sub>Sn</sub><sup>•</sup> defect with Cr'<sub>Sn</sub>. According to Eq. (2), the addition of Ta<sub>2</sub>O<sub>5</sub> causes the formation of Ta<sub>Sn</sub><sup>•</sup>. This is equivalent to an electronic defect and can be represented by:



An excess of [h<sup>•</sup>] resulting from a higher concentration of Ta<sub>2</sub>O<sub>5</sub> could cause a decrease in  $E_B$  value by the reaction illustrated in Eq. (10), since the smallest  $E_B$  values were obtained for 0.065 mol% SCTaCr systems in all the atmospheres used (see Table 2). The excess of electron holes could decrease the effect of the negative charged defects at the interface, responsible for electric barrier formation.

Thus, a reduction in the interface state density of the system could be expected through an excess of electron holes. This is the same analytical treatment given by Ikeda et al.<sup>42</sup> in the TiO<sub>2</sub> rutile structure, which possesses the same structure as the SnO<sub>2</sub> semiconductor used in this study. Ikeda et al. concluded that the segregation of solutes of positive and negative effective charge, i.e. donors (Nb<sub>2</sub>O<sub>5</sub>) and acceptors (Al<sub>2</sub>O<sub>3</sub>),

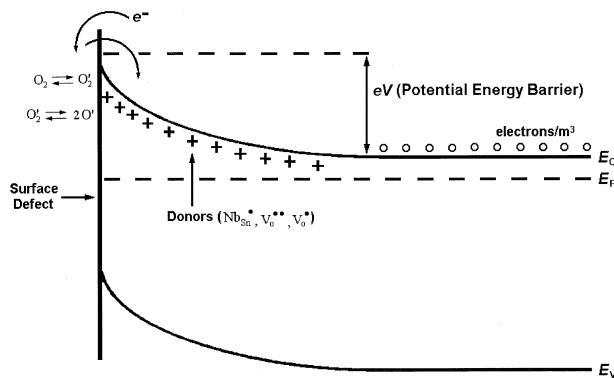


Fig. 5. Schematic representation describing some possible surface and bulk phenomena and its effect in voltage barrier in  $\text{SnO}_2$  based varistor systems.

depends on the overall doping level, temperature, and oxygen pressure. When there is an excess of donor  $\text{Nb}_2\text{O}_5$ , it is compensated in the lattice by titanium vacancies and, in this kind of composition, a segregation of  $\text{Nb}_{\text{Ti}}^+$ , is seemed.  $\text{Cr}_2\text{O}_3$  and  $\text{Nb}_2\text{O}_5$  dopants cause a similar effect on the  $\text{TiO}_2$  lattice, compared to  $\text{SnO}_2$ , and this system has also a varistor behavior, as already reported in the literature.<sup>19</sup> Considering that the addition of  $\text{Nb}_2\text{O}_5$  in  $\text{SnO}_2$  has similar effect to that of  $\text{Ta}_2\text{O}_5$  in  $\text{SnO}_2$ , the present hypothesis appears plausible.

Therefore, the role of  $\text{Co}_{\text{Sn}}''$ ,  $\text{Cr}_{\text{Sn}}'$ ,  $\text{Sn}_{\text{Sn}}''$ ,  $\text{V}_{\text{Sn}}''''$  and  $\text{V}_{\text{Sn}}''$  (due to the reduction of  $\text{Sn}^{+4}$  to  $\text{Sn}^{+2}$  in the interstitial sites) would be related to the increase the  $\text{O}_2'$ ,  $\text{O}'$  and  $\text{O}''$  adsorption at the grain boundary interface, causing a decrease in the conductivity by the donation of electrons to the  $\text{O}_2$  absorbed at the grain boundary surface. The role of  $\text{Co}_{\text{Sn}}''$ ,  $\text{Cr}_{\text{Sn}}'$ ,  $\text{Sn}_{\text{Sn}}''$ ,  $\text{V}_{\text{Sn}}''''$  and  $\text{V}_{\text{Sn}}''$  species would be to generate sites to promote the adsorption of electrophilic species (forming a depletion layer). The experimental data presented in this paper reinforce this hypothesis, since both  $\alpha$  and  $E_B$  are quite dependent on the oxidizing atmosphere. Experiments are under way to elucidate these statements.

In summary, the level of negative defect sites created at the grain boundary interface is of fundamental importance for good nonlinearity properties in  $\text{SnO}_2$  varistor systems.

#### 4. Conclusions

The experimental results indicate that the  $\alpha$  and  $E_B$  of the SCTaCr varistor system depend on the  $\text{Ta}_2\text{O}_5$  concentration. Concentrations up to 0.05 mol% increase those properties due to tin vacancy formation. Higher concentrations, however, decrease these properties owing to decreased trap states at the grain boundary.

The partial oxygen pressure in the sintering atmosphere of the  $\text{SnO}_2$  based varistor is a decisive factor in the varistor properties. The degradation of the voltage

barrier of  $\text{SnO}_2$  based varistor, when heat treated in nitrogen, and the subsequent restoration of this voltage barrier by heat treating in an oxygen atmosphere suggests that the chemical origin of the interface states may be due to the chemisorbed oxygen on the grain surfaces. The results suggest that the maximum concentration of oxygen species at grain boundary interface depends on the level of adsorption sites that are created by negative defects such as  $\text{Co}_{\text{Sn}}''$ ,  $\text{Cr}_{\text{Sn}}'$ ,  $\text{Sn}_{\text{Sn}}''$ ,  $\text{V}_{\text{Sn}}''''$  and  $\text{V}_{\text{Sn}}''$ .

#### Acknowledgements

The financial support of this research by CNPq, FINEP, PRONEX and FAPESP is gratefully acknowledged.

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